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### **Embedded - System On Chip (SoC): The Heart of Modern Embedded Systems**

**Embedded - System On Chip (SoC)** refers to an integrated circuit that consolidates all the essential components of a computer system into a single chip. This includes a microprocessor, memory, and other peripherals, all packed into one compact and efficient package. SoCs are designed to provide a complete computing solution, optimizing both space and power consumption, making them ideal for a wide range of embedded applications.

#### **What are Embedded - System On Chip (SoC)?**

**System On Chip (SoC)** integrates multiple functions of a computer or electronic system onto a single chip. Unlike traditional multi-chip solutions, SoCs combine a central

#### **Details**

Product Status	Active
Architecture	MCU, FPGA
Core Processor	Quad ARM® Cortex®-A53 MPCore™ with CoreSight™, Dual ARM® Cortex™-R5 with CoreSight™, ARM Mali™-400 MP2
Flash Size	-
RAM Size	256KB
Peripherals	DMA, WDT
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, MMC/SD/SDIO, SPI, UART/USART, USB OTG
Speed	533MHz, 600MHz, 1.3GHz
Primary Attributes	Zynq®UltraScale+™ FPGA, 1143K+ Logic Cells
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	1760-BBGA, FCBGA
Supplier Device Package	1760-FCBGA (42.5x42.5)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xczu19eg-2ffvc1760e">https://www.e-xfl.com/product-detail/xilinx/xczu19eg-2ffvc1760e</a>

## V<sub>IN</sub> Maximum Allowed AC Voltage Overshoot and Undershoot

Table 6: V<sub>IN</sub> Maximum Allowed AC Voltage Overshoot and Undershoot for HD I/O Banks<sup>(1)</sup>

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
V <sub>CCO</sub> + 0.30	100%	-0.30	100%
V <sub>CCO</sub> + 0.35	100%	-0.35	90%
V <sub>CCO</sub> + 0.40	100%	-0.40	78%
V <sub>CCO</sub> + 0.45	100%	-0.45	40%
V <sub>CCO</sub> + 0.50	100%	-0.50	24%
V <sub>CCO</sub> + 0.55	100%	-0.55	18.0%
V <sub>CCO</sub> + 0.60	100%	-0.60	13.0%
V <sub>CCO</sub> + 0.65	100%	-0.65	10.8%
V <sub>CCO</sub> + 0.70	92%	-0.70	9.0%
V <sub>CCO</sub> + 0.75	92%	-0.75	7.0%
V <sub>CCO</sub> + 0.80	92%	-0.80	6.0%
V <sub>CCO</sub> + 0.85	92%	-0.85	5.0%
V <sub>CCO</sub> + 0.90	92%	-0.90	4.0%
V <sub>CCO</sub> + 0.95	92%	-0.95	2.5%

**Notes:**

1. A total of 200 mA per bank should not be exceeded.

Table 7: V<sub>IN</sub> Maximum Allowed AC Voltage Overshoot and Undershoot for HP I/O Banks<sup>(1)(2)</sup>

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
V <sub>CCO</sub> + 0.30	100%	-0.30	100%
V <sub>CCO</sub> + 0.35	100%	-0.35	100%
V <sub>CCO</sub> + 0.40	92%	-0.40	92%
V <sub>CCO</sub> + 0.45	50%	-0.45	50%
V <sub>CCO</sub> + 0.50	20%	-0.50	20%
V <sub>CCO</sub> + 0.55	10%	-0.55	10%
V <sub>CCO</sub> + 0.60	6%	-0.60	6%
V <sub>CCO</sub> + 0.65	2%	-0.65	2%
V <sub>CCO</sub> + 0.70	2%	-0.70	2%

**Notes:**

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20  $\mu$ s.

# Power Supply Sequencing

## PS Power-On/Off Power Supply Sequencing

The low-power domain (LPD) must operate before the full-power domain (FPD) can function. The low-power and full-power domains can be powered simultaneously. The PS\_POR\_B input must be asserted to GND during the power-on sequence (see [Table 37](#)). The FPD (when used) must be powered before PS\_POR\_B is released.

To achieve minimum current draw and ensure that the I/Os are 3-stated at power-on, the recommended power-on sequence for the low-power domain (LPD) is listed. The recommended power-off sequence is the reverse of the power-on sequence.

1.  $V_{CC\_PSINTLP}$
2.  $V_{CC\_PSAUX}$ ,  $V_{CC\_PSADC}$ , and  $V_{CC\_PSPLL}$  in any order or simultaneously.
3.  $V_{CCO\_PSIO}$

To achieve minimum current draw and ensure that the I/Os are 3-stated at power-on, the recommended power-on sequence for the full-power domain (FPD) is listed. The recommended power-off sequence is the reverse of the power-on sequence.

1.  $V_{CC\_PSINTFP}$  and  $V_{CC\_PSINTFP\_DDR}$  driven from the same supply source.
2.  $V_{PS\_MGTRAVCC}$  and  $V_{CC\_PSDDR\_PLL}$  in any order or simultaneously.
3.  $V_{PS\_MGTRAVTT}$  and  $V_{CCO\_PSDDR}$  in any order or simultaneously.

## PL Power-On/Off Power Supply Sequencing

The recommended power-on sequence is  $V_{CCINT}$ ,  $V_{CCINT\_IO}/V_{CCBRAM}/V_{CCINT\_VCU}$ ,  $V_{CCAUX}/V_{CCAUX\_IO}$ , and  $V_{CCO}$  to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If  $V_{CCINT}$  and  $V_{CCINT\_IO}/V_{CCBRAM}$  have the same recommended voltage levels, they can be powered by the same supply and ramped simultaneously.  $V_{CCINT\_IO}$  must be connected to  $V_{CCBRAM}$ . If  $V_{CCAUX}/V_{CCAUX\_IO}$  and  $V_{CCO}$  have the same recommended voltage levels, they can be powered by the same supply and ramped simultaneously.  $V_{CCAUX}$  and  $V_{CCAUX\_IO}$  must be connected together.  $V_{CCADC}$  and  $V_{REF}$  can be powered at any time and have no power-up sequencing requirements.

The recommended power-on sequence to achieve minimum current draw for the GTH or GTY transceivers is  $V_{CCINT}$ ,  $V_{MGTAVCC}$ ,  $V_{MGTAVTT}$  OR  $V_{MGTAVCC}$ ,  $V_{CCINT}$ ,  $V_{MGTAVTT}$ . There is no recommended sequencing for  $V_{MGTAVCCAUX}$ . Both  $V_{MGTAVCC}$  and  $V_{CCINT}$  can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from  $V_{MGTAVTT}$  can be higher than specifications during power-up and power-down.

## PS-PL Power Sequencing

The PS and PL power supplies are fully independent. All PS power supplies can be powered before or after any PL power supplies. The PS and PL power regions are isolated to prevent damage.

## Power Supply Requirements

[Table 10](#) shows the minimum current, in addition to  $I_{CCQ}$  maximum, required by each Zynq UltraScale+ device for proper power-on and configuration. If the current minimums shown in [Table 10](#) are met, the device powers on after all supplies have passed through their power-on reset threshold voltages. The device must not be configured until after  $V_{CCINT}$  is applied. Once initialized and configured, use the Xilinx Power Estimator (XPE) tools to estimate current drain on these supplies.

[Table 10: Power-on Current by Device](#) <sup>(1)</sup>

$I_{CC}$ Min =	$I_{CCQ} +$	XCZU2	XCZU3	XCZU4	XCZU5	XCZU6	XCZU7	XCZU9	XCZU11	XCZU15	XCZU17	XCZU19	Units
$I_{CCINTMIN}$	$I_{CCINTQ} +$	464	464	770	770	1800	1514	1800	1961	2242	3433	3433	mA
$I_{CCINT\_JOMIN} +$ $I_{CCBRAMMIN}$	$I_{CCBRAMQ} +$ $I_{CCINT\_IOQ} +$	155	155	257	257	600	505	600	654	748	1145	1145	mA
$I_{CCOMIN}$	$I_{CCOQ} +$	50	50	50	50	50	50	50	55	63	96	96	mA
$I_{CCAUXMIN} +$ $I_{CCAUX\_IOMIN}$	$I_{CCAUXQ} +$ $I_{CCAUX\_IOQ} +$	111	111	386	386	650	362	650	709	810	1240	1240	mA

### Notes:

1. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at [www.xilinx.com/power](http://www.xilinx.com/power)) to estimate power-on current for all supplies.

[Table 11](#) shows the power supply ramp time.

[Table 11: Power Supply Ramp Time](#)

Symbol	Description	Min	Max	Units
$T_{VCCINT}$	Ramp time from GND to 95% of $V_{CCINT}$ .	0.2	40	ms
$T_{VCCINT\_IO}$	Ramp time from GND to 95% of $V_{CCINT\_IO}$ .	0.2	40	ms
$T_{VCCINT\_VCU}$	Ramp time from GND to 95% of $V_{CCINT\_VCU}$ .	0.2	40	ms
$T_{VCCO}$	Ramp time from GND to 95% of $V_{CCO}$ .	0.2	40	ms
$T_{VCCAUX}$	Ramp time from GND to 95% of $V_{CCAUX}$ .	0.2	40	ms
$T_{VCCBRAM}$	Ramp time from GND to 95% of $V_{CCBRAM}$ .	0.2	40	ms
$T_{MGTAVCC}$	Ramp time from GND to 95% of $V_{MGTAVCC}$ .	0.2	40	ms
$T_{MGTAVTT}$	Ramp time from GND to 95% of $V_{MGTAVTT}$ .	0.2	40	ms
$T_{MGTVCVAUX}$	Ramp time from GND to 95% of $V_{MGTVCVAUX}$ .	0.2	40	ms
$T_{VCC\_PSINTFP}$	Ramp time from GND to 95% of $V_{CC\_PSINTFP}$ .	0.2	40	ms
$T_{VCC\_PSINTLP}$	Ramp time from GND to 95% of $V_{CC\_PSINTLP}$ .	0.2	40	ms
$T_{VCC\_PSAUX}$	Ramp time from GND to 95% of $V_{CC\_PSAUX}$ .	0.2	40	ms
$T_{VCC\_PSINTFP\_DDR}$	Ramp time from GND to 95% of $V_{CC\_PSINTFP\_DDR}$ .	0.2	40	ms
$T_{VCC\_PSADC}$	Ramp time from GND to 95% of $V_{CC\_PSADC}$ .	0.2	40	ms
$T_{VCC\_PSPLL}$	Ramp time from GND to 95% of $V_{CC\_PSPLL}$ .	0.2	40	ms
$T_{PS\_MGTRAVCC}$	Ramp time from GND to 95% of $V_{CC\_MGTRAVCC}$ .	0.2	40	ms
$T_{PS\_MGTRAVTT}$	Ramp time from GND to 95% of $V_{CC\_MGTRAVTT}$ .	0.2	40	ms

# AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in the Vivado® Design Suite as outlined in [Table 25](#).

**Table 25: Speed Specification Version By Device**

2017.1	Device
1.08	XCZU4CG, XCZU4EG, XCZU4EV, XCZU5CG, XCZU5EG, XCZU5EV, XCZU11EG
1.10	XCZU2CG, XCZU2EG, XCZU3CG, XCZU3EG, XCZU6CG, XCZU6EG, XCZU7CG, XCZU7EG, XCZU7EV, XCZU9CG, XCZU9EG, XCZU15EG, XCZU17EG, XCZU19EG

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

## Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

## Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

## Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to production before faster speed grades.

# Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Zynq UltraScale+ MPSoC.

Table 26: Speed Grade Designations by Device (Cont'd)

Device	Speed Grade, Temperature Ranges, and V <sub>CCINT</sub> Operating Voltages		
	Advance	Preliminary	Production
XCZU5EG	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU5EV	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU6CG	-2LE (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V) -1LI (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.72V)		-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V) -1I (V <sub>CCINT</sub> = 0.85V)
XCZU6EG	-3E (V <sub>CCINT</sub> = 0.90V) -2LE (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V) -1LI (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.72V)		-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V) -1I (V <sub>CCINT</sub> = 0.85V)
XCZU7CG	-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU7EG	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU7EV	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU9CG	-2LE (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V) -1LI (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.72V)		-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V) -1I (V <sub>CCINT</sub> = 0.85V)
XCZU9EG	-3E (V <sub>CCINT</sub> = 0.90V) -2LE (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V) -1LI (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.72V)		-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V) -1I (V <sub>CCINT</sub> = 0.85V)

Table 30: PS DDR Performance (Cont'd)

Memory Standard	Package	DRAM Type	Speed Grade						Units	
			-3		-2		-1			
			Min	Max	Min	Max	Min	Max		
DDR3	All FFV packages, FBVB900 and SFVC784	Single rank component	664	2133	664	2133	664	2133	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1866	664	1866	664	1866	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1600	664	1600	664	1600	Mb/s	
	SFVA625	Single rank component	664	1866	664	1866	664	1866	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1600	664	1600	664	1600	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1333	664	1333	664	1333	Mb/s	
	SBVA484	Single rank component	664	1066	664	1066	664	1066	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1066	664	1066	664	1066	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1066	664	1066	664	1066	Mb/s	
DDR3L	All FFV packages, FBVB900 and SFVC784	Single rank component	664	1866	664	1866	664	1866	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1600	664	1600	664	1600	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1333	664	1333	664	1333	Mb/s	
	SFVA625	Single rank component	664	1600	664	1600	664	1600	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1333	664	1333	664	1333	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1066	664	1066	664	1066	Mb/s	
	SBVA484	Single rank component	664	1066	664	1066	664	1066	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1066	664	1066	664	1066	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1066	664	1066	664	1066	Mb/s	
LPDDR3	All FFV packages, FBVB900 and SFVC784	Single die package <sup>(6)</sup>	664	1600	664	1600	664	1600	Mb/s	
		Dual die package <sup>(6)</sup>	664	1333	664	1333	664	1333	Mb/s	
	SFVA625	Single die package <sup>(6)</sup>	664	1333	664	1333	664	1333	Mb/s	
		Dual die package <sup>(6)</sup>	664	1066	664	1066	664	1066	Mb/s	
	SBVA484	Single die package <sup>(6)</sup>	664	1066	664	1066	664	1066	Mb/s	
		Dual die package <sup>(6)</sup>	664	1066	664	1066	664	1066	Mb/s	

**Notes:**

1. Dual in-line memory module (DIMM) includes RDIMM, SODIMM, and UDIMM.
2. Includes: 1 rank 1 slot, dual-die package 2 rank.
3. Includes: 2 rank 1 slot.
4. Dual die package includes single die with ECC.
5. LPDDR4 support is only available as a 32-bit interface.
6. 64-bit LPDDR3 interface performance values are defined without ECC support.

Table 31: PS NAND NV-DDR Synchronous Performance

Memory Standard	Mode	Speed Grade			Units
		-3	-2	-1	
		Max	Max	Max	
NV-DDR <sup>(1)</sup>	5	200	200	200	Mb/s
	4	166.6	166.6	166.6	Mb/s
	3	133.3	133.3	133.3	Mb/s
	2	100	100	100	Mb/s
	1	66.6	66.6	66.6	Mb/s
	0	40	40	40	Mb/s

**Notes:**

1. The PS NAND memory controller interface for NV-DDR switching characteristics meets the requirements of the ONFI 3.1 specification.

Table 32: PS NAND SDR Asynchronous Performance

Memory Standard	Mode	Speed Grade			Units
		-3	-2	-1	
		Max	Max	Max	
SDR <sup>(1)(2)</sup>	5	50	50	50	Mb/s
	4	40	40	40	Mb/s
	3	33.3	33.3	33.3	Mb/s
	2	28.5	28.5	28.5	Mb/s
	1	20	20	20	Mb/s
	0	10	10	10	Mb/s

**Notes:**

1. The PS NAND memory controller interface for SDR switching characteristics meets the requirements of the ONFI 3.1 specification.
2. The NAND controller reference clock frequency maximum is 83 MHz.

Table 33: PS-PL Interface Performance

Symbol	Description	Min	Max	Units
FEMIOGEMCLK	EMIO gigabit Ethernet controller maximum frequency.	–	125	MHz
FEMIOSDCLK	EMIO SD controller maximum frequency.	–	25	MHz
FEMIOSPICLK	EMIO SPI controller maximum frequency.	–	25	MHz
FEMIOTRACECLK	EMIO trace controller maximum frequency.	–	125	MHz
FFCIDMACLK	Flow control interface DMA maximum frequency.	–	333	MHz
FAXICLK	Maximum AXI interface performance.	–	333	MHz
FDPLIVEVIDEO	DisplayPort controller live video interface maximum frequency.	–	300	MHz

## PS eMMC Standard Interface

Table 46: eMMC Standard Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
<b>eMMC Standard Interface</b>				
T <sub>DCEMMCHSCLK</sub>	eMMC clock duty cycle.	45	55	%
T <sub>E姚MCHSCKO</sub>	Clock to output delay, all outputs.	-2.0	4.5	ns
T <sub>E姚MCHSDCK</sub>	Input setup time, all inputs.	2.0	-	ns
T <sub>E姚MCHSCKD</sub>	Input hold time, all inputs.	2.0	-	ns
F <sub>E姚MCHSCLK</sub>	eMMC clock frequency.	-	25	MHz
<b>eMMC High-Speed SDR Interface</b>				
T <sub>DCEMMCHSCLK</sub>	eMMC high-speed SDR clock duty cycle.	45	55	%
T <sub>E姚MCHSCKO</sub>	Clock to output delay, all outputs. <sup>(2)</sup>	3.2	16.8	ns
T <sub>E姚MCHSDIVW</sub>	Input valid data window. <sup>(3)</sup>	0.4	-	UI
F <sub>E姚MCHSCLK</sub>	eMMC high speed SDR clock frequency.	-	50	MHz
<b>eMMC High-Speed DDR Interface</b>				
T <sub>DCEMMCDRCLK</sub>	eMMC high-speed DDR clock duty cycle.	45	55	%
T <sub>E姚MCDRSCKO1</sub>	Data clock to output delay. <sup>(2)</sup>	2.7	7.3	ns
T <sub>E姚MCSDRIVW</sub>	Input valid data window. <sup>(3)</sup>	3.5	-	ns
T <sub>E姚MCDDRCKO2</sub>	Command clock to output delay.	3.2	16	ns
T <sub>E姚MCDDRCK2</sub>	Command input setup time.	3.9	-	ns
T <sub>E姚MCDDRCKD2</sub>	Command input hold time.	2.5	-	ns
F <sub>E姚MCDDRCLK</sub>	eMMC high-speed DDR clock frequency.	-	50	MHz
<b>eMMC HS200 Interface</b>				
T <sub>DCEMMCHS200CLK</sub>	eMMC HS200 clock duty cycle.	40	60	%
T <sub>E姚MCHS200CKO</sub>	Clock to output delay, all outputs. <sup>(2)</sup>	1.0	3.4	ns
T <sub>E姚MCSDRIVW</sub>	Input valid data window. <sup>(3)</sup>	0.4	-	UI
F <sub>E姚MCHS200CLK</sub>	eMMC HS200 clock frequency.	-	200	MHz

### Notes:

1. The test conditions for eMMC standard mode use an 8 mA drive strength, fast slew rate, and a 30 pF load. For eMMC high-speed mode, the test conditions use a 12 mA drive strength, fast slew rate, and a 30 pF load. For other eMMC modes, the test conditions use a 12 mA drive strength, fast slew rate, and a 15 pF load.
2. This specification is achieved using pre-determined DLL tuning.
3. This specification is required for capturing input data using DLL tuning.

## PS I2C Controller Interface

Table 47: I2C Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
<b>I2C Fast-mode Interface</b>				
T <sub>I2CFCKL</sub>	SCL Low time.	1.3	–	μs
T <sub>I2CFCKH</sub>	SCL High time.	0.6	–	μs
T <sub>I2CFCKO</sub>	SDA clock to out delay.	–	900	ns
T <sub>I2CFDCK</sub>	SDA input setup time.	100	–	ns
F <sub>I2CFCLK</sub>	SCL clock frequency.	–	400	KHz
<b>I2C Standard-mode Interface</b>				
T <sub>I2CSCKL</sub>	SCL Low time.	4.7	–	μs
T <sub>I2CSCKH</sub>	SCL High time.	4.0	–	μs
T <sub>I2CSCKO</sub>	SDA clock to out delay.	–	3450	ns
T <sub>I2CSDCK</sub>	SDA input setup time.	250	–	ns
F <sub>I2CSCLK</sub>	SCL clock frequency.	–	100	KHz

**Notes:**

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

# PS-GTR Transceiver

Table 56: PS-GTR Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
D <sub>VPPIN</sub>	Differential peak-to-peak input voltage (external AC coupled).		100	—	1200	mV
V <sub>IN</sub>	Single-ended input voltage. Voltage measured at the pin referenced to GND.		75	—	V <sub>PS_MGTRAVCC</sub>	mV
V <sub>CMIN</sub>	Common mode input voltage.		—	0	—	mV
D <sub>VPPOUT</sub>	Differential peak-to-peak output voltage. <sup>(1)</sup>	Transmitter output swing is set to maximum value.	800	—	—	mV
V <sub>CMOUTAC</sub>	Common mode output voltage: AC coupled (equation based).		V <sub>PS_MGTRAVCC</sub> – D <sub>VPPOUT</sub> /2			mV
R <sub>IN</sub>	Differential input resistance.		—	100	—	Ω
R <sub>OUT</sub>	Differential output resistance.		—	100	—	Ω
R <sub>MGTRREF</sub>	Resistor value between calibration resistor pin to GND.		497.5	500	502.5	Ω
T <sub>OSKEW</sub>	Transmitter output pair (TXP and TXN) intra-pair skew (All packages).		—	—	20	ps
C <sub>EXT</sub>	Recommended external AC coupling capacitor. <sup>(2)</sup>		—	100	—	nF

**Notes:**

1. The output swing and pre-emphasis levels are programmable using the attributes discussed in the *Zynq UltraScale+ MPSoC Technical Reference Manual* (UG1085), and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

Table 57: PS-GTR Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V <sub>IDIFF</sub>	Differential peak-to-peak input voltage.	250	—	2000	mV
R <sub>IN</sub>	Differential input resistance.	—	100	—	Ω
C <sub>EXT</sub>	Required external AC coupling capacitor.	—	10	—	nF

Table 58: PS-GTR Transceiver Performance

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
F <sub>GTRMAX</sub>	PS-GTR maximum line rate.	6.0	6.0	6.0	Gb/s
F <sub>GTRMIN</sub>	PS-GTR minimum line rate.	1.25	1.25	1.25	Gb/s

Table 59: PS-GTR Transceiver PLL/Lock Time Adaptation

Symbol	Description	Min	Typ	Max	Units
T <sub>LOCK</sub>	Initial PLL lock.	—	—	0.11	ms
T <sub>DLOCK</sub>	Clock recovery phase acquisition and adaptation time.	—	—	24 × 10 <sup>6</sup>	UI

Table 72: MIPI D-PHY Performance

Description	I/O Bank Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units	
		0.90V	0.85V		0.72V			
		-3 <sup>(1)</sup>	-2 <sup>(1)</sup>	-1	-2	-1		
MIPI D-PHY transmitter or receiver.	HP	1500	1500	1260	1260	1260	Mb/s	

**Notes:**

1. In the SBVA484 package, the data rate is 1260 Mb/s.

Table 73: LVDS Native-Mode 1000BASE-X Support<sup>(1)</sup>

Description	I/O Bank Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages				
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	-1
1000BASE-X	HP	Yes				

**Notes:**

1. 1000BASE-X support is based on the *IEEE Standard for CSMA/CD Access Method and Physical Layer Specifications* (IEEE Std 802.3-2008).

Table 74 provides the maximum data rates for applicable memory standards using the Zynq UltraScale+ MPSoC memory PHY. Refer to [Memory Interfaces](#) for the complete list of memory interface standards supported and detailed specifications. The final performance of the memory interface is determined through a complete design implemented in the Vivado Design Suite, following guidelines in the *UltraScale Architecture PCB Design Guide* ([UG583](#)), electrical analysis, and characterization of the system.

Table 74: Maximum Physical Interface (PHY) Rate for Memory Interfaces

Memory Standard	Package <sup>(1)</sup>	DRAM Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
DDR4	All FFV packages and FBVB900	Single rank component	2666	2666	2400	2400	2133	Mb/s	
		1 rank DIMM <sup>(2)(3)(4)</sup>	2400	2400	2133	2133	1866	Mb/s	
		2 rank DIMM <sup>(2)(5)</sup>	2133	2133	1866	1866	1600	Mb/s	
		4 rank DIMM <sup>(2)(6)</sup>	1600	1600	1333	1333	N/A	Mb/s	
	SFVC784	Single rank component	2400	2400	2133	2133	1866	Mb/s	
		1 rank DIMM <sup>(2)(3)</sup>	2133	2133	1866	1866	1600	Mb/s	
		2 rank DIMM <sup>(2)(5)</sup>	1866	1866	1600	1600	1600	Mb/s	
DDR3	All FFV packages and FBVB900	Single rank component	2133	2133	2133	2133	1866	Mb/s	
		1 rank DIMM <sup>(2)(3)</sup>	1866	1866	1866	1866	1600	Mb/s	
		2 rank DIMM <sup>(2)(5)</sup>	1600	1600	1600	1600	1333	Mb/s	
		4 rank DIMM <sup>(2)(6)</sup>	1066	1066	1066	1066	800	Mb/s	
	SFVC784	Single rank component	1866	1866	1866	1866	1600	Mb/s	
		1 rank DIMM <sup>(2)(3)</sup>	1600	1600	1600	1600	1600	Mb/s	
		2 rank DIMM <sup>(2)(5)</sup>	1600	1600	1600	1600	1333	Mb/s	
		4 rank DIMM <sup>(2)(6)</sup>	1066	1066	1066	1066	800	Mb/s	

Table 74: Maximum Physical Interface (PHY) Rate for Memory Interfaces (Cont'd)

Memory Standard	Package <sup>(1)</sup>	DRAM Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units		
			0.90V		0.85V		0.72V			
			-3	-2	-1	-2	-1			
DDR3L	All FFV packages and FBVB900	Single rank component	1866	1866	1866	1866	1600	Mb/s		
		1 rank DIMM <sup>(2)(3)</sup>	1600	1600	1600	1600	1333	Mb/s		
		2 rank DIMM <sup>(2)(5)</sup>	1333	1333	1333	1333	1066	Mb/s		
		4 rank DIMM <sup>(2)(6)</sup>	800	800	800	800	606	Mb/s		
	SFVC784	Single rank component	1600	1600	1600	1600	1600	Mb/s		
		1 rank DIMM <sup>(2)(3)</sup>	1600	1600	1600	1600	1333	Mb/s		
		2 rank DIMM <sup>(2)(5)</sup>	1333	1333	1333	1333	1066	Mb/s		
		4 rank DIMM <sup>(2)(6)</sup>	800	800	800	800	606	Mb/s		
QDR II+	All	Single rank component <sup>(7)</sup>	633	633	600	600	550	MHz		
RLDRAM 3	All FFV packages and FBVB900	Single rank component	1200	1200	1066	1066	933	MHz		
	SFVC784	Single rank component	1066	1066	933	933	800	MHz		
QDR IV XP	All	Single rank component	1066	1066	1066	933	933	MHz		
LPDDR3	All	Single rank component	1600	1600	1600	1600	1600	Mb/s		

**Notes:**

1. The SBVA484 and SFVA625 packages do not support the PL memory interfaces.
2. Dual in-line memory module (DIMM) includes RDIMM, SODIMM, UDIMM, and LRDIMM.
3. Includes: 1 rank 1 slot, DDP 2 rank, LRDIMM 2 or 4 rank 1 slot.
4. For the DDR4 DDP components at -3 and -2 speed grades and V<sub>CCINT</sub> = 0.85V, the maximum data rate is 2133 Mb/s for six or more DDP devices. For five or less DDP devices, use the single rank DIMM data rates for the -3 and -2 speed grades at 0.85V.
5. Includes: 2 rank 1 slot, 1 rank 2 slot, LRDIMM 2 rank 2 slot.
6. Includes: 2 rank 2 slot, 4 rank 1 slot.
7. The QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations.

Table 75: IOB High Density (HD) Switching Characteristics (Cont'd)

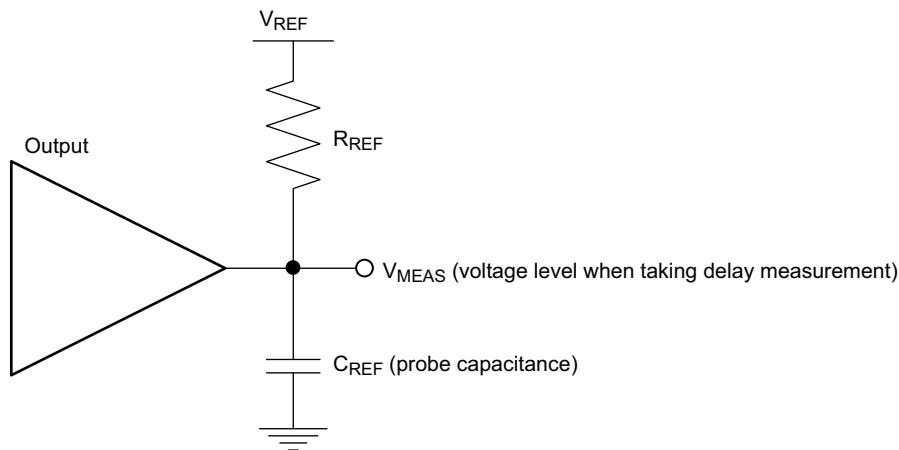
I/O Standards	T <sub>INBUF_DELAY_PAD_I</sub>					T <sub>OUTBUF_DELAY_O_PAD</sub>					T <sub>OUTBUF_DELAY_TD_PAD</sub>					Units
	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
HSTL_I_F	0.856	0.856	0.900	0.856	0.900	1.611	1.611	1.762	1.611	1.762	1.313	1.313	1.417	1.313	1.417	ns
HSTL_I_S	0.856	0.856	0.900	0.856	0.900	1.798	1.798	1.913	1.798	1.913	1.630	1.630	1.780	1.630	1.780	ns
HSUL_12_F	0.780	0.780	0.867	0.780	0.867	1.573	1.573	1.703	1.573	1.703	1.222	1.222	1.335	1.222	1.335	ns
HSUL_12_S	0.780	0.780	0.867	0.780	0.867	1.711	1.711	1.864	1.711	1.864	1.536	1.536	1.665	1.536	1.665	ns
LVCMOS12_F_12	0.918	0.918	0.976	0.918	0.976	1.689	1.689	1.856	1.689	1.856	1.202	1.202	1.317	1.202	1.317	ns
LVCMOS12_F_4	0.918	0.918	0.976	0.918	0.976	1.742	1.742	1.922	1.742	1.922	1.353	1.353	1.478	1.353	1.478	ns
LVCMOS12_F_8	0.918	0.918	0.976	0.918	0.976	1.714	1.714	1.879	1.714	1.879	1.292	1.292	1.432	1.292	1.432	ns
LVCMOS12_S_12	0.918	0.918	0.976	0.918	0.976	2.073	2.073	2.247	2.073	2.247	1.581	1.581	1.717	1.581	1.717	ns
LVCMOS12_S_4	0.918	0.918	0.976	0.918	0.976	1.979	1.979	2.182	1.979	2.182	1.633	1.633	1.772	1.633	1.772	ns
LVCMOS12_S_8	0.918	0.918	0.976	0.918	0.976	2.205	2.205	2.406	2.205	2.406	1.767	1.767	1.928	1.767	1.928	ns
LVCMOS15_F_12	0.905	0.905	0.958	0.905	0.958	1.713	1.713	1.892	1.713	1.892	1.275	1.275	1.428	1.275	1.428	ns
LVCMOS15_F_16	0.905	0.905	0.958	0.905	0.958	1.722	1.722	1.881	1.722	1.881	1.260	1.260	1.407	1.260	1.407	ns
LVCMOS15_F_4	0.905	0.905	0.958	0.905	0.958	1.825	1.825	1.959	1.825	1.959	1.453	1.453	1.557	1.453	1.557	ns
LVCMOS15_F_8	0.905	0.905	0.958	0.905	0.958	1.778	1.778	1.930	1.778	1.930	1.378	1.378	1.458	1.378	1.458	ns
LVCMOS15_S_12	0.905	0.905	0.958	0.905	0.958	1.991	1.991	2.139	1.991	2.139	1.516	1.516	1.648	1.516	1.648	ns
LVCMOS15_S_16	0.905	0.905	0.958	0.905	0.958	2.172	2.172	2.389	2.172	2.389	1.707	1.707	1.888	1.707	1.888	ns
LVCMOS15_S_4	0.905	0.905	0.958	0.905	0.958	2.313	2.313	2.483	2.313	2.483	1.952	1.952	2.123	1.952	2.123	ns
LVCMOS15_S_8	0.905	0.905	0.958	0.905	0.958	2.170	2.170	2.400	2.170	2.400	1.817	1.817	1.984	1.817	1.984	ns
LVCMOS18_F_12	0.915	0.915	0.958	0.915	0.958	1.805	1.805	1.962	1.805	1.962	1.383	1.383	1.471	1.383	1.471	ns
LVCMOS18_F_16	0.915	0.915	0.958	0.915	0.958	1.785	1.785	1.917	1.785	1.917	1.338	1.338	1.446	1.338	1.446	ns
LVCMOS18_F_4	0.915	0.915	0.958	0.915	0.958	1.868	1.868	2.013	1.868	2.013	1.472	1.472	1.599	1.472	1.599	ns
LVCMOS18_F_8	0.915	0.915	0.958	0.915	0.958	1.797	1.797	1.979	1.797	1.979	1.384	1.384	1.487	1.384	1.487	ns
LVCMOS18_S_12	0.915	0.915	0.958	0.915	0.958	2.201	2.201	2.408	2.201	2.408	1.762	1.762	1.894	1.762	1.894	ns
LVCMOS18_S_16	0.915	0.915	0.958	0.915	0.958	2.173	2.173	2.362	2.173	2.362	1.702	1.702	1.834	1.702	1.834	ns
LVCMOS18_S_4	0.915	0.915	0.958	0.915	0.958	2.346	2.346	2.567	2.346	2.567	1.951	1.951	2.092	1.951	2.092	ns
LVCMOS18_S_8	0.915	0.915	0.958	0.915	0.958	2.292	2.292	2.511	2.292	2.511	1.848	1.848	2.008	1.848	2.008	ns
LVCMOS25_F_12	0.988	0.988	1.042	0.988	1.042	2.153	2.153	2.453	2.153	2.453	1.692	1.692	1.856	1.692	1.856	ns
LVCMOS25_F_16	0.988	0.988	1.042	0.988	1.042	2.105	2.105	2.406	2.105	2.406	1.623	1.623	1.786	1.623	1.786	ns
LVCMOS25_F_4	0.988	0.988	1.042	0.988	1.042	2.344	2.344	2.554	2.344	2.554	1.842	1.842	2.039	1.842	2.039	ns
LVCMOS25_F_8	0.988	0.988	1.042	0.988	1.042	2.184	2.184	2.516	2.184	2.516	1.726	1.726	1.910	1.726	1.910	ns
LVCMOS25_S_12	0.988	0.988	1.042	0.988	1.042	2.558	2.558	2.840	2.558	2.840	1.971	1.971	2.194	1.971	2.194	ns
LVCMOS25_S_16	0.988	0.988	1.042	0.988	1.042	2.449	2.449	2.740	2.449	2.740	1.852	1.852	2.063	1.852	2.063	ns
LVCMOS25_S_4	0.988	0.988	1.042	0.988	1.042	2.770	2.770	3.066	2.770	3.066	2.224	2.224	2.458	2.224	2.458	ns
LVCMOS25_S_8	0.988	0.988	1.042	0.988	1.042	2.663	2.663	2.963	2.663	2.963	2.091	2.091	2.373	2.091	2.373	ns
LVCMOS33_F_12	1.154	1.154	1.213	1.154	1.213	2.415	2.415	2.651	2.415	2.651	1.754	1.754	1.915	1.754	1.915	ns
LVCMOS33_F_16	1.154	1.154	1.213	1.154	1.213	2.383	2.383	2.603	2.383	2.603	1.734	1.734	1.869	1.734	1.869	ns
LVCMOS33_F_4	1.154	1.154	1.213	1.154	1.213	2.541	2.541	2.765	2.541	2.765	1.932	1.932	2.135	1.932	2.135	ns
LVCMOS33_F_8	1.154	1.154	1.213	1.154	1.213	2.603	2.603	2.822	2.603	2.822	1.937	1.937	2.130	1.937	2.130	ns
LVCMOS33_S_12	1.154	1.154	1.213	1.154	1.213	2.705	2.705	3.047	2.705	3.047	2.049	2.049	2.318	2.049	2.318	ns
LVCMOS33_S_16	1.154	1.154	1.213	1.154	1.213	2.714	2.714	3.024	2.714	3.024	2.028	2.028	2.232	2.028	2.232	ns
LVCMOS33_S_4	1.154	1.154	1.213	1.154	1.213	2.999	2.999	3.340	2.999	3.340	2.320	2.320	2.610	2.320	2.610	ns

Table 76: IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standards	T <sub>INBUF_DELAY_PAD_I</sub>					T <sub>OUTBUF_DELAY_O_PAD</sub>					T <sub>OUTBUF_DELAY_TD_PAD</sub>					Units
	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
DIFF_SSTL12_F	0.394	0.394	0.402	0.394	0.402	0.412	0.412	0.430	0.412	0.430	0.538	0.538	0.566	0.538	0.566	ns
DIFF_SSTL12_M	0.394	0.394	0.402	0.394	0.402	0.553	0.553	0.584	0.553	0.584	0.641	0.641	0.676	0.641	0.676	ns
DIFF_SSTL12_S	0.394	0.394	0.402	0.394	0.402	0.758	0.758	0.808	0.758	0.808	0.823	0.823	0.879	0.823	0.879	ns
DIFF_SSTL135_DCI_F	0.371	0.371	0.402	0.371	0.402	0.411	0.411	0.428	0.411	0.428	0.537	0.537	0.565	0.537	0.565	ns
DIFF_SSTL135_DCI_M	0.371	0.371	0.402	0.371	0.402	0.551	0.551	0.582	0.551	0.582	0.645	0.645	0.685	0.645	0.685	ns
DIFF_SSTL135_DCI_S	0.371	0.371	0.402	0.371	0.402	0.746	0.746	0.799	0.746	0.799	0.829	0.829	0.893	0.829	0.893	ns
DIFF_SSTL135_F	0.375	0.375	0.402	0.375	0.402	0.408	0.408	0.428	0.408	0.428	0.528	0.528	0.561	0.528	0.561	ns
DIFF_SSTL135_M	0.375	0.375	0.402	0.375	0.402	0.555	0.555	0.585	0.555	0.585	0.641	0.641	0.679	0.641	0.679	ns
DIFF_SSTL135_S	0.375	0.375	0.402	0.375	0.402	0.772	0.772	0.823	0.772	0.823	0.827	0.827	0.878	0.827	0.878	ns
DIFF_SSTL15_DCI_F	0.397	0.397	0.417	0.397	0.417	0.412	0.412	0.429	0.412	0.429	0.531	0.531	0.563	0.531	0.563	ns
DIFF_SSTL15_DCI_M	0.397	0.397	0.417	0.397	0.417	0.553	0.553	0.583	0.553	0.583	0.645	0.645	0.685	0.645	0.685	ns
DIFF_SSTL15_DCI_S	0.397	0.397	0.417	0.397	0.417	0.768	0.768	0.822	0.768	0.822	0.847	0.847	0.912	0.847	0.912	ns
DIFF_SSTL15_F	0.404	0.404	0.417	0.404	0.417	0.424	0.424	0.445	0.424	0.445	0.551	0.551	0.577	0.551	0.577	ns
DIFF_SSTL15_M	0.404	0.404	0.417	0.404	0.417	0.554	0.554	0.585	0.554	0.585	0.639	0.639	0.677	0.639	0.677	ns
DIFF_SSTL15_S	0.404	0.404	0.417	0.404	0.417	0.767	0.767	0.817	0.767	0.817	0.813	0.813	0.867	0.813	0.867	ns
DIFF_SSTL18_I_DCI_F	0.320	0.320	0.336	0.320	0.336	0.445	0.445	0.461	0.445	0.461	0.566	0.566	0.595	0.566	0.595	ns
DIFF_SSTL18_I_DCI_M	0.320	0.320	0.336	0.320	0.336	0.554	0.554	0.585	0.554	0.585	0.644	0.644	0.683	0.644	0.683	ns
DIFF_SSTL18_I_DCI_S	0.320	0.320	0.336	0.320	0.336	0.762	0.762	0.818	0.762	0.818	0.837	0.837	0.899	0.837	0.899	ns
DIFF_SSTL18_I_F	0.316	0.316	0.336	0.316	0.336	0.454	0.454	0.476	0.454	0.476	0.578	0.578	0.608	0.578	0.608	ns
DIFF_SSTL18_I_M	0.316	0.316	0.336	0.316	0.336	0.571	0.571	0.603	0.571	0.603	0.652	0.652	0.692	0.652	0.692	ns
DIFF_SSTL18_I_S	0.316	0.316	0.336	0.316	0.336	0.782	0.782	0.835	0.782	0.835	0.816	0.816	0.870	0.816	0.870	ns
HSLVDCI_15_F	0.393	0.393	0.415	0.393	0.415	0.425	0.425	0.443	0.425	0.443	0.548	0.548	0.579	0.548	0.579	ns
HSLVDCI_15_M	0.393	0.393	0.415	0.393	0.415	0.552	0.552	0.581	0.552	0.581	0.644	0.644	0.684	0.644	0.684	ns
HSLVDCI_15_S	0.393	0.393	0.415	0.393	0.415	0.748	0.748	0.802	0.748	0.802	0.827	0.827	0.890	0.827	0.890	ns
HSLVDCI_18_F	0.424	0.424	0.447	0.424	0.447	0.445	0.445	0.461	0.445	0.461	0.566	0.566	0.595	0.566	0.595	ns
HSLVDCI_18_M	0.424	0.424	0.447	0.424	0.447	0.567	0.567	0.598	0.567	0.598	0.658	0.658	0.699	0.658	0.699	ns
HSLVDCI_18_S	0.424	0.424	0.447	0.424	0.447	0.761	0.761	0.817	0.761	0.817	0.836	0.836	0.900	0.836	0.900	ns
HSTL_I_12_F	0.378	0.378	0.399	0.378	0.399	0.423	0.423	0.443	0.423	0.443	0.553	0.553	0.582	0.553	0.582	ns
HSTL_I_12_M	0.378	0.378	0.399	0.378	0.399	0.551	0.551	0.582	0.551	0.582	0.642	0.642	0.679	0.642	0.679	ns
HSTL_I_12_S	0.378	0.378	0.399	0.378	0.399	0.750	0.750	0.799	0.750	0.799	0.813	0.813	0.868	0.813	0.868	ns
HSTL_I_18_F	0.322	0.322	0.339	0.322	0.339	0.456	0.456	0.474	0.456	0.474	0.576	0.576	0.606	0.576	0.606	ns
HSTL_I_18_M	0.322	0.322	0.339	0.322	0.339	0.569	0.569	0.602	0.569	0.602	0.653	0.653	0.692	0.653	0.692	ns
HSTL_I_18_S	0.322	0.322	0.339	0.322	0.339	0.781	0.781	0.833	0.781	0.833	0.816	0.816	0.871	0.816	0.871	ns
HSTL_I_DCI_12_F	0.378	0.378	0.399	0.378	0.399	0.406	0.406	0.429	0.406	0.429	0.534	0.534	0.564	0.534	0.564	ns
HSTL_I_DCI_12_M	0.378	0.378	0.399	0.378	0.399	0.556	0.556	0.586	0.556	0.586	0.654	0.654	0.694	0.654	0.694	ns
HSTL_I_DCI_12_S	0.378	0.378	0.399	0.378	0.399	0.754	0.754	0.803	0.754	0.803	0.842	0.842	0.907	0.842	0.907	ns
HSTL_I_DCI_18_F	0.321	0.321	0.339	0.321	0.339	0.445	0.445	0.461	0.445	0.461	0.566	0.566	0.595	0.566	0.595	ns
HSTL_I_DCI_18_M	0.321	0.321	0.339	0.321	0.339	0.554	0.554	0.585	0.554	0.585	0.643	0.643	0.684	0.643	0.684	ns
HSTL_I_DCI_18_S	0.321	0.321	0.339	0.321	0.339	0.761	0.761	0.817	0.761	0.817	0.836	0.836	0.900	0.836	0.900	ns
HSTL_I_DCI_F	0.393	0.393	0.415	0.393	0.415	0.431	0.431	0.445	0.431	0.445	0.555	0.555	0.575	0.555	0.575	ns
HSTL_I_DCI_M	0.393	0.393	0.415	0.393	0.415	0.552	0.552	0.581	0.552	0.581	0.644	0.644	0.684	0.644	0.684	ns

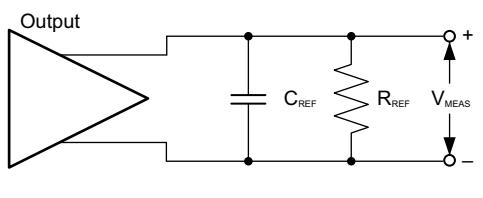
## Output Delay Measurement Methodology

Output delays are measured with short output traces. Standard termination was used for all testing. The propagation delay of the trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in [Figure 1](#) and [Figure 2](#).



X16654-101316

**Figure 1: Single-Ended Test Setup**



X16640-101316

**Figure 2: Differential Test Setup**

Parameters  $V_{REF}$ ,  $R_{REF}$ ,  $C_{REF}$ , and  $V_{MEAS}$  fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using this method:

1. Simulate the output driver of choice into the generalized test setup using values from [Table 79](#).
2. Record the time to  $V_{MEAS}$ .
3. Simulate the output driver of choice into the actual PCB trace and load using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to  $V_{MEAS}$ .
5. Compare the results of [step 2](#) and [step 4](#). The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 91: Global Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
<b>Input Setup and Hold Time Relative to Global Clock Input Signal using SSTL15 Standard. (1)(2)(3)</b>									
$T_{PSMMCMCC\_ZU2}$	Global clock input and input flip-flop (or latch) with MMCM.	Setup Hold	XCZU2	N/A	1.83	1.96	2.29	2.48	ns
$T_{PHMMCMCC\_ZU2}$					-0.19	-0.19	0.13	0.13	ns
$T_{PSMMCMCC\_ZU3}$		Setup Hold	XCZU3	N/A	1.83	1.96	2.29	2.48	ns
$T_{PHMMCMCC\_ZU3}$					-0.19	-0.19	0.13	0.13	ns
$T_{PSMMCMCC\_ZU4}$		Setup Hold	XCZU4	1.96	1.96	2.10	2.49	2.59	ns
$T_{PHMMCMCC\_ZU4}$					-0.12	-0.12	-0.12	0.27	0.48
$T_{PSMMCMCC\_ZU5}$		Setup Hold	XCZU5	1.96	1.96	2.10	2.49	2.59	ns
$T_{PHMMCMCC\_ZU5}$					-0.12	-0.12	-0.12	0.27	0.48
$T_{PSMMCMCC\_ZU6}$		Setup Hold	XCZU6	1.97	2.00	2.12	2.26	2.44	ns
$T_{PHMMCMCC\_ZU6}$					-0.11	-0.11	-0.11	0.16	0.18
$T_{PSMMCMCC\_ZU7}$		Setup Hold	XCZU7	1.91	1.91	2.02	2.45	2.70	ns
$T_{PHMMCMCC\_ZU7}$					-0.14	-0.14	-0.14	0.37	0.38
$T_{PSMMCMCC\_ZU9}$		Setup Hold	XCZU9	1.97	2.00	2.12	2.26	2.44	ns
$T_{PHMMCMCC\_ZU9}$					-0.11	-0.11	-0.11	0.16	0.18
$T_{PSMMCMCC\_ZU11}$		Setup Hold	XCZU11	2.08	2.08	2.23	2.59	2.75	ns
$T_{PHMMCMCC\_ZU11}$					-0.08	-0.08	0.04	0.35	0.74
$T_{PSMMCMCC\_ZU15}$		Setup Hold	XCZU15	1.96	1.99	2.12	2.26	2.44	ns
$T_{PHMMCMCC\_ZU15}$					-0.10	-0.10	-0.10	0.17	0.19
$T_{PSMMCMCC\_ZU17}$		Setup Hold	XCZU17	1.89	1.89	2.03	2.36	2.55	ns
$T_{PHMMCMCC\_ZU17}$					-0.16	-0.16	-0.16	0.31	0.34
$T_{PSMMCMCC\_ZU19}$		Setup Hold	XCZU19	1.89	1.89	2.03	2.36	2.55	ns
$T_{PHMMCMCC\_ZU19}$					-0.16	-0.16	-0.16	0.31	0.34

**Notes:**

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, slowest temperature, and slowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, fastest temperature, and fastest voltage.
2. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 103: GTH Transceiver Transmitter Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
T <sub>J2.5</sub>	Total jitter <sup>(3)(4)</sup>	2.5 Gb/s <sup>(6)</sup>	–	–	0.20	UI
D <sub>J2.5</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.10	UI
T <sub>J1.25</sub>	Total jitter <sup>(3)(4)</sup>	1.25 Gb/s <sup>(7)</sup>	–	–	0.15	UI
D <sub>J1.25</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.06	UI
T <sub>J500</sub>	Total jitter <sup>(3)(4)</sup>	500 Mb/s <sup>(8)</sup>	–	–	0.10	UI
D <sub>J500</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.03	UI

**Notes:**

1. Using same REFCLK input with TX phase alignment enabled for up to four consecutive transmitters (one fully populated GTH Quad) at the maximum line rate.
2. Using QPLL\_FBDIV = 40, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. Using CPLL\_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
4. All jitter values are based on a bit-error ratio of 10<sup>-12</sup>.
5. CPLL frequency at 3.2 GHz and TXOUT\_DIV = 2.
6. CPLL frequency at 2.5 GHz and TXOUT\_DIV = 2.
7. CPLL frequency at 2.5 GHz and TXOUT\_DIV = 4.
8. CPLL frequency at 2.0 GHz and TXOUT\_DIV = 8.

Table 104: GTH Transceiver Receiver Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F <sub>GTHR</sub> X	Serial data rate		0.500	–	F <sub>GTHMAX</sub>	Gb/s
R <sub>XSST</sub>	Receiver spread-spectrum tracking <sup>(1)</sup>	Modulated at 33 kHz	–5000	–	0	ppm
R <sub>XRL</sub>	Run length (CID)		–	–	256	UI
R <sub>XPPMTOL</sub>	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	–1250	–	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	–700	–	700	ppm
		Bit rates > 8.0 Gb/s	–200	–	200	ppm

**SJ Jitter Tolerance<sup>(2)</sup>**

J <sub>T_SJ16.375</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	16.375 Gb/s	0.30	–	–	UI
J <sub>T_SJ15.0</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	15.0 Gb/s	0.30	–	–	UI
J <sub>T_SJ14.1</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	14.1 Gb/s	0.30	–	–	UI
J <sub>T_SJ13.1</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	13.1 Gb/s	0.30	–	–	UI
J <sub>T_SJ12.5</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	12.5 Gb/s	0.30	–	–	UI
J <sub>T_SJ11.3</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	11.3 Gb/s	0.30	–	–	UI
J <sub>T_SJ10.32_QPLL</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	10.32 Gb/s	0.30	–	–	UI
J <sub>T_SJ10.32_CPLL</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	10.32 Gb/s	0.30	–	–	UI
J <sub>T_SJ9.953_QPLL</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	9.953 Gb/s	0.30	–	–	UI
J <sub>T_SJ9.953_CPLL</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	9.953 Gb/s	0.30	–	–	UI
J <sub>T_SJ8.0</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	8.0 Gb/s	0.42	–	–	UI
J <sub>T_SJ6.6_CPLL</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	6.6 Gb/s	0.44	–	–	UI
J <sub>T_SJ5.0</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	5.0 Gb/s	0.44	–	–	UI
J <sub>T_SJ4.25</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	4.25 Gb/s	0.44	–	–	UI
J <sub>T_SJ3.2</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	3.2 Gb/s <sup>(4)</sup>	0.45	–	–	UI

Table 104: GTH Transceiver Receiver Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
J <sub>T</sub> _SJ2.5	Sinusoidal jitter (CPLL) <sup>(3)</sup>	2.5 Gb/s <sup>(5)</sup>	0.30	—	—	UI
J <sub>T</sub> _SJ1.25	Sinusoidal jitter (CPLL) <sup>(3)</sup>	1.25 Gb/s <sup>(6)</sup>	0.30	—	—	UI
J <sub>T</sub> _SJ500	Sinusoidal jitter (CPLL) <sup>(3)</sup>	500 Mb/s <sup>(7)</sup>	0.30	—	—	UI
<b>SJ Jitter Tolerance with Stressed Eye<sup>(2)</sup></b>						
J <sub>T</sub> _TJSE3.2	Total jitter with stressed eye <sup>(8)</sup>	3.2 Gb/s	0.70	—	—	UI
J <sub>T</sub> _TJSE6.6		6.6 Gb/s	0.70	—	—	UI
J <sub>T</sub> _SJSE3.2	Sinusoidal jitter with stressed eye <sup>(8)</sup>	3.2 Gb/s	0.10	—	—	UI
J <sub>T</sub> _SJSE6.6		6.6 Gb/s	0.10	—	—	UI

**Notes:**

1. Using RXOUT\_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of  $10^{-12}$ .
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT\_DIV = 2.
5. CPLL frequency at 2.5 GHz and RXOUT\_DIV = 2.
6. CPLL frequency at 2.5 GHz and RXOUT\_DIV = 4.
7. CPLL frequency at 2.0 GHz and RXOUT\_DIV = 8.
8. Composite jitter with RX equalizer enabled. DFE disabled.

## GTH Transceiver Electrical Compliance

The *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) contains recommended use modes that ensure compliance for the protocols listed in [Table 105](#). The transceiver wizard provides the recommended settings for those use cases and for protocol specific characteristics.

## GTY Transceiver Electrical Compliance

The *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)) contains recommended use modes that ensure compliance for the protocols listed in [Table 117](#). The transceiver wizard provides the recommended settings for those use cases and for protocol specific characteristics.

*Table 117: GTY Transceiver Protocol List*

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
CAUI-4	IEEE 802.3-2012	25.78125	Compliant
28 Gb/s backplane	CEI-25G-LR	25–28.05	Compliant
Interlaken	OIF-CEI-6G, OIF-CEI-11GSR, OIF-CEI-28G-MR	4.25–25.78125	Compliant
100GBASE-KR4	IEEE 802.3bj-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
100GBASE-CR4	IEEE 802.3bj-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
50GBASE-KR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
50GBASE-CR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
25GBASE-KR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
25GBASE-CR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
OTU4 (OTL4.4) CFP2	OIF-CEI-28G-VSR	27.952493–32.75	Compliant
OTU4 (OTL4.4) CFP	OIF-CEI-11G-MR	11.18–13.1	Compliant
CAUI-10	IEEE 802.3-2012	10.3125	Compliant
nPPI	IEEE 802.3-2012	10.3125	Compliant
10GBASE-KR <sup>(2)</sup>	IEEE 802.3-2012	10.3125	Compliant
SFP+	SFF-8431 (SR and LR)	9.95328–11.10	Compliant
XFP	INF-8077i, revision 4.5	10.3125	Compliant
RXAUI	CEI-6G-SR	6.25	Compliant
XAUI	IEEE 802.3-2012	3.125	Compliant
1000BASE-X	IEEE 802.3-2012	1.25	Compliant
5.0G Ethernet	IEEE 802.3bx (PAR)	5	Compliant
2.5G Ethernet	IEEE 802.3bx (PAR)	2.5	Compliant
HiGig, HiGig+, HiGig2	IEEE 802.3-2012	3.74, 6.6	Compliant
QSGMII	QSGMII v1.2 (Cisco System, ENG-46158)	5	Compliant
OTU2	ITU G.8251	10.709225	Compliant
OTU4 (OTL4.10)	OIF-CEI-11G-SR	11.180997	Compliant
OC-3/12/48/192	GR-253-CORE	0.1555–9.956	Compliant
PCIe Gen1, 2, 3	PCI Express base 3.0	2.5, 5.0, and 8.0	Compliant
SDI <sup>(3)</sup>	SMPTE 424M-2006	0.27–2.97	Compliant
UHD-SDI <sup>(3)</sup>	SMPTE ST-2081 6G, SMPTE ST-2082 12G	6 and 12	Compliant
Hybrid memory cube (HMC)	HMC-15G-SR	10, 12.5, and 15.0	Compliant
MoSys bandwidth engine	CEI-11-SR and CEI-11-SR (overclocked)	10.3125, 15.5	Compliant
CPRI	CPRI_v_6_1_2014-07-01	0.6144–12.165	Compliant
Passive optical network (PON)	10G-EPON, 1G-EPON, NG-PON2, XG-PON, and 2.5G-PON	0.155–10.3125	Compliant
JESD204a/b	OIF-CEI-6G, OIF-CEI-11G	3.125–12.5	Compliant

Table 124: PL SYSMON Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
<b>On-Chip Sensor Accuracy</b>						
Temperature sensor error <sup>(1)(3)</sup>		T <sub>j</sub> = -55°C to 125°C (with external REF)	-	-	±3	°C
		T <sub>j</sub> = -55°C to 110°C (with internal REF)	-	-	±3.5	°C
		T <sub>j</sub> = 110°C to 125°C (with internal REF)	-	-	±5	°C
Supply sensor error <sup>(4)</sup>		Supply voltages 0.72V to 1.2V, T <sub>j</sub> = -40°C to 100°C (with external REF)	-	-	±0.5	%
		Supply voltages 0.72V to 1.2V, T <sub>j</sub> = -55°C to 125°C (with external REF)	-	-	±1.0	%
		All other supply voltages, T <sub>j</sub> = -40°C to 100°C (with external REF)	-	-	±1.0	%
		All other supply voltages, T <sub>j</sub> = -55°C to 125°C (with external REF)	-	-	±2.0	%
		Supply voltages 0.72V to 1.2V, T <sub>j</sub> = -40°C to 100°C (with internal REF)	-	-	±1.0	%
		Supply voltages 0.72V to 1.2V, T <sub>j</sub> = -55°C to 125°C (with internal REF)	-	-	±2.0	%
		All other supply voltages, T <sub>j</sub> = -40°C to 100°C (with internal REF)	-	-	±1.5	%
		All other supply voltages, T <sub>j</sub> = -55°C to 125°C (with internal REF)	-	-	±2.5	%
<b>Conversion Rate<sup>(5)</sup></b>						
Conversion time—continuous	t <sub>CONV</sub>	Number of ADCCLK cycles	26	-	32	Cycles
Conversion time—event	t <sub>CONV</sub>	Number of ADCCLK cycles	-	-	21	Cycles
DRP clock frequency	DCLK	DRP clock frequency	8	-	250	MHz
ADC clock frequency	ADCCLK	Derived from DCLK	1	-	5.2	MHz
DCLK duty cycle			40	-	60	%
<b>SYSMON Reference<sup>(6)</sup></b>						
External reference	V <sub>REFP</sub>	Externally supplied reference voltage	1.20	1.25	1.30	V
On-chip reference		Ground V <sub>REFP</sub> pin to AGND, T <sub>j</sub> = -40°C to 100°C	1.2375	1.25	1.2625	V
		Ground V <sub>REFP</sub> pin to AGND, T <sub>j</sub> = -55°C to 125°C	1.225	1.25	1.275	V

**Notes:**

1. ADC offset errors are removed by enabling the ADC automatic offset calibration feature. The values are specified for when this feature is enabled.
2. See the *Analog Input* section in the *UltraScale Architecture System Monitor User Guide* ([UG580](#)).
3. When reading temperature values directly from the PMBus interface, the SYSMON has a +4°C offset due to the transfer function used by the PMBus application. For example, the external REF temperature sensor error's range of ±3°C becomes +1°C to +7°C when the temperature is read through the PMBus interface.
4. Supply sensor offset and gain errors are removed by enabling the automatic offset and gain calibration feature. The values are specified for when this feature is enabled.
5. See the *Adjusting the Acquisition Settling Time* section in the *UltraScale Architecture System Monitor User Guide* ([UG580](#)).
6. Any variation in the reference voltage from the nominal V<sub>REFP</sub> = 1.25V and V<sub>REFN</sub> = 0V will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by ±4% is permitted.